# Notice of References Cited

Application/Control No. 09/6<del>25,390</del> 767,810

Examiner

Jonathan D. Schlaifer

Applicant(s)/Patent Under Reexamination HICKMAN ET AL.

Art Unit 2178

Page 1 of 2

### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,490,589	12-2002	Weider et al.	707/100
	В	US-6,112,210	08-2000	Nori et al.	707/103R
	C	US-5,644,692	07-1997	Eick, Stephen Gregory	345/833
	D	US-5,696,539	12-1997	Welti et al.	345/603
	Е	US-5,708,825	01-1998	Sotomayor, Bernardo Rafael	715/501.1
	F	US-6,533,822	03-2003	Kupiec, Julian M.	715/531
	G	US-6,032,132	02-2000	Nelson, Nickolas B.	705/34
	Н	US-6,026,387	02-2000	Kesel, Brad	706/52
	ı	US-6,161,130	12-2000	Horvitz et al.	709/206
	J	US-6,192,165	02-2001	Irons, Steven W.	382/306
	К	US-5,893,916	04-1999	Dooley, Marilyn R.	715/523
	L	US-6,457,143	09-2002	Yue, Po Cheung	714/43
	М	US-5,732,216	03-1998	Logan et al.	709/203

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q				1	
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited

Application/Control No.

O9/625,390 767/8/0

Examiner

Jonathan D. Schlaifer

Applicant(s)/Patent Under
Reexamination
HICKMAN ET AL.

Art Unit
Page 2 of 2

**U.S. PATENT DOCUMENTS** 

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,446,061	09-2002	Doerre et al.	707/3
	В	US-5,204,960	04-1993	Smith et al.	717/145
	O	US-6,138,149	10-2000	Ohmura, Kazunori	709/218
	D	US-6,253,231	06-2001	Fujii, Toshiya	709/206
	Е	US-6,052,717	04-2000	Reynolds et al.	709/218
	F	US-5,710,883	01-1998	Hong et al.	709/246
	G	US-5,566,330	10-1996	Sheffield, Kim A.	707/4
	Η	US-			
		US-			
	J	US-	-		
	К	US-			
	L	US-			
	М	US-			

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0				,	
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	Х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.